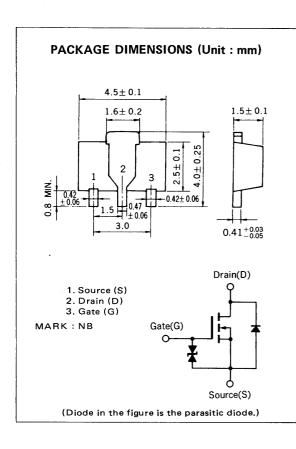


# MOS FIELD EFFECT TRANSISTOR **2SK1483**

# N-CHANNEL MOS FET FOR SWITCHING



The 2SK1483 is an N-channel vertical type MOS FET switching device which can be directly driven from an IC operating with a 5 V single power supply. The device features low ON-state resistance and outstanding switching characteristics and thus is ideal for driving actuators such as motors, solenoids, and relays.

#### **FEATURES**

- Can be driven directly from an IC operating with a 5 V single power supply.
- Low ON-state resistance

 $R_{DS(on)}$  = 0.8  $\Omega$  MAX. at  $V_{GS}$  = 4 V,  $I_D$  = 0.5 A  $R_{DS(on)}$  = 0.4  $\Omega$  MAX. at  $V_{GS}$  = 10 V,  $I_D$  = 0.5 A

• Can be used complementary with the 2SJ197.

### QUALITY GRADE

Standard

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

# ABSOLUTE MAXIMUM RATINGS ( $T_a = 25$ °C)

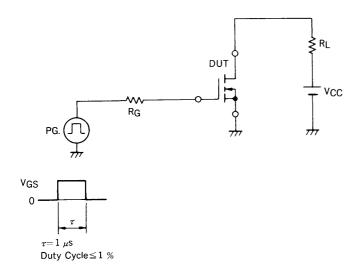
| PARAMETER               | SYMBOL                | RATING      | UNIT | TEST CONDITIONS                                |
|-------------------------|-----------------------|-------------|------|--|
| Drain to Source Voltage | V <sub>DSS</sub>      | 30          | V    | V <sub>GS</sub> = 0                            |
| Gate to Source Voltage  | V <sub>GSS</sub>      | ±20         | V    | V <sub>DS</sub> = 0                            |
| Drain Current (DC)      | ID(DC)                | ±2.0        | А    |  |
| Drain Current (pulse)   | <sup>1</sup> D(pulse) | ±4.0        | Α    | PW ≤ 10 ms, Duty Cycle ≤ 50 %                  |
| Total Power Dissipation | P <sub>T</sub>        | 2.0         | w    | when using ceramic board of<br>16 cm² x 0.7 mm |
| Channel Temperature     | T <sub>ch</sub>       | 150         | °C   |  |
| Storage Temperature     | T <sub>stg</sub>      | -55 to +150 | °C   |  |

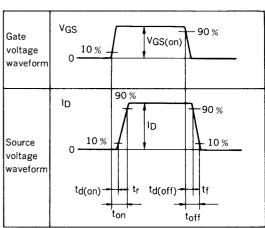


# ELECTRICAL CHARACTERISTICS ( $T_a = 25$ °C)

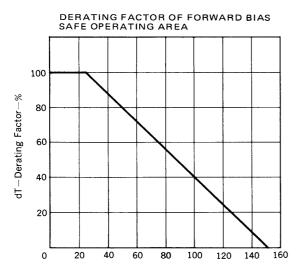
| PARAMETER                             | SYMBOL               | MIN.  | TYP. | MAX. | UNIT | TEST CONDITIONS   |
|---------------------------------------|----------------------|-------|------|------|------|---|
| Drain Leakage Current                 | IDSS                 |       |      | 10   | μΑ   | V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0   |
| Gate Leakage Current                  | IGSS                 |       |      | ±10  | μΑ   | $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0$   |
| Gate Cutoff Voltage                   | V <sub>GS(off)</sub> | 1.3   | 1.8  | 2.5  | V    | V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA   |
| Forward Transfer Admittance           | ly <sub>fs</sub> l   | 0.4   |      |      | S    | V <sub>DS</sub> = 10 V, I <sub>D</sub> = 0.5 A  |
| Drain to Source On-State Resistance 1 | R <sub>DS(on)1</sub> |       | 0.19 | 0.8  | Ω    | V <sub>GS</sub> = 4.0 V, I <sub>D</sub> = 0.5 A   |
| Drain to Source On-State Resistance 2 | R <sub>DS(on)2</sub> |       | 0.15 | 0.4  | Ω    | V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.5 A  |
| Input Capacitance                     | C <sub>iss</sub>     |       | 230  |      | рF   |   |
| Output Capacitance                    | Coss                 |       | 170  |      | рF   | V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0, f = 1.0 MHz  |
| Feedback Capacitance                  | C <sub>rss</sub>     |       | 45   |      | рF   |   |
| On-State Delay Time                   | <sup>t</sup> d(on)   |       | 15   |      | ns   |   |
| Rise Time                             | t <sub>r</sub>       |       | 50   |      | ns   | V <sub>GS(on)</sub> = 10 V, R <sub>G</sub> = 10 Ω<br>V <sub>DD</sub> = 25 V, I <sub>D</sub> = 0.5 A |
| Off-State Delay Time                  | <sup>t</sup> d(off)  | , , , | 420  |      | ns   | VDD = 25 V, 1D = 0.5 A<br>RL = 50 Ω   |
| Fall Time                             | tf                   |       | 240  |      | ns   |   |

# SWITCHING TIME MEASUREMENT CIRCUIT & MEASUREMENT CONDITIONS

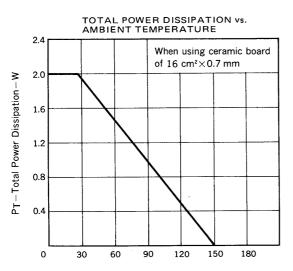




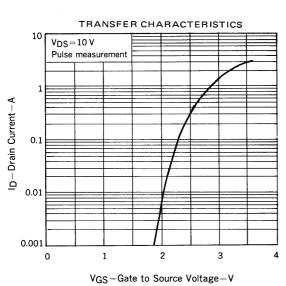
# CHARACTERISTIC CURVES (Ta = 25 °C)



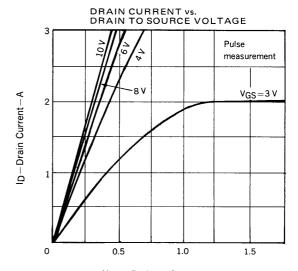
T<sub>C</sub>-Case Temperature-°C



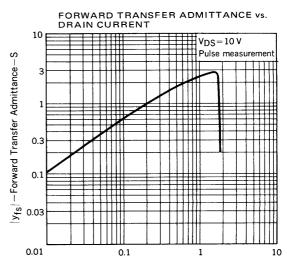
 $T_a-Ambient\ Temperature-{}^{\circ}C$ 



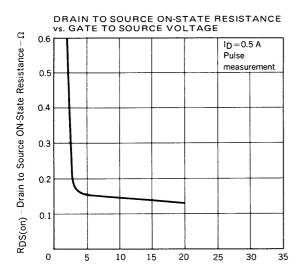
 $v_{DS}\!-\!\text{Drain to Source Voltage}\!-\!v$ 



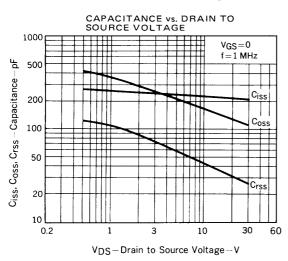
VDS-Drain to Source Voltage-V



ID-Drain Current-mA



 $V_{GS}\!-\!Gate\ to\ Source\ Voltage\!-\!V$ 



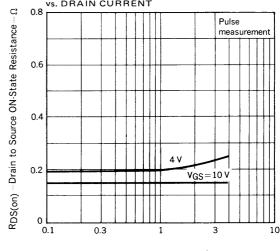
SOURCE TO DRAIN DIODE FORWARD VOLTAGE

1.6 VGS=0 Pulse measurement

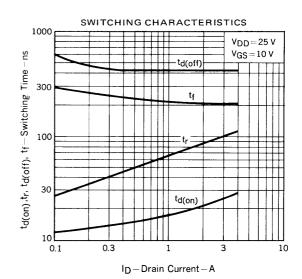
1.2 1.0 0.8 0.6 0.8 1.0 1.2 1.4 0.6 0.8 1.0 1.2 1.4

 $v_{SD}\!-\!\text{Source to Drain Voltage}\!-\!\text{V}$ 

DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



 $I_D\!-\!Drain\ Current\!-\!A$ 



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# RECOMMENDED SOLDERING CONDITIONS

Solder this product under the following recommended conditions.

For soldering methods or soldering conditions other than those recommended in the table, please consult our NEC salespeople.

### SURFACE MOUNT TYPE

For details of the soldering conditions, refer to the surface-mount type Device Packaging Manual (IEI-1207).

| Soldering method | Soldering conditions   | Recommended condition code |
|------------------|--|----------------------------|
| Infrared reflow  | Package peak temperature: 230 °C,<br>Soldering time: 30 sec max. (at 210 °C min.)<br>No. of applied times: Once<br>Limit on No. of days*: None | IR30-00                    |
| VPS              | Package peak temperature: 215 °C Soldering time: 40 sec max. (at 200 °C min.) No. of applied times: Once Limit on No. of days*: None           | VP15-00                    |
| Wave soldering   | Solder bath temperature: 260 °C max. Soldering time: 10 sec max. No. of applied times: Once Limit on No. of days*: None                        | WS60-00                    |

<sup>\*:</sup> Refers to the number of days to be kept in storage after unsealing the dry pack. The storage conditions are 25 °C and 65 % RH.

Note: Do not use any two of the above soldering methods in combination.

## REFERENCE

| Document Name  | Document No. |  |
|--|--------------|--|
| NEC semiconductor device reliability/quality control system. | TEI-1202     |  |
| Quality grade on NEC semiconductor devices.                  | IEI-1209     |  |
| Semiconductor device mounting technology manual.             | IEI-1207     |  |
| Semiconductor device package manual,                         | IEI-1213     |  |
| Guide to quality assurance for semiconductor devices.        | MEI-1202     |  |
| Semiconductor selection guide.                               | MF-1134      |  |

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The devices listed in this document are not suitable for use in aerospace equipment, submarine cables, nuclear reactor control systems and life support systems. If customers intend to use NEC devices for above applications or they intend to use "Standard" quality grade NEC devices for applications not intended by NEC, please contact our sales people in advance.

Application examples recommended by NEC Corporation

Standard: Computer, Office equipment, Communication equipment, Test and Measurement equipment, Machine tools, Industrial robots, Audio and Visual equipment, Other consumer products, etc.

Special: Automotive and Transportation equipment, Traffic control systems, Antidisaster systems, Anticrime systems, etc.

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